

March 2008

## **FDP047N08**

# N-Channel PowerTrench<sup>®</sup> MOSFET 75V, 164A, 4.7m $\Omega$

#### **Features**

- $R_{DS(on)} = 3.8 m\Omega$  (Typ.)@  $V_{GS} = 10 V$ ,  $I_{D} = 80 A$
- · Fast switching speed
- · Low gate charge
- High performance trench technology for extremely low R<sub>DS(on)</sub>
- · High power and current handling capability
- · RoHS compliant

## **Description**

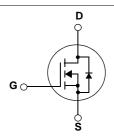
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## **Application**

• DC to DC convertors / Synchronous Rectification







## **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter	Parameter		Units
V <sub>DSS</sub>	Drain to Source Voltage			75	V
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
1	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		164*	А
ID.	DrainCurrent	-Continuous (T <sub>C</sub> = 100°C)	-Continuous (T <sub>C</sub> = 100°C)		А
I <sub>DM</sub>	Drain Current	- Pulsed	- Pulsed (Note 1)		А
E <sub>AS</sub>	Single Pulsed Avalanche	Energy (Note 2)		670	mJ
dv/dt	Peak Diode Recovery dv/	It (Note 3)		3.0	V/ns
D	Dawas Dissipation	$(T_C = 25^{\circ}C)$		268	W
$P_{D}$	Power Dissipation	- Derate above 25°C		1.79	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range		-55 to +175	°C
TL	Maximum Lead Temperat 1/8" from Case for 5 Seco	ure for Soldering Purpose, nds	3		

<sup>\*</sup>Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 80A.

#### **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.56	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

## Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP047N08	FDP047N08	TO-220	-	-	50

### **Electrical Characteristics**

Parameter Test Conditions		Min.	Тур.	Max.	Units
eteristics					
Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	75	-	-	V
Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.02	-	V/°C
Zoro Coto Voltago Proin Current	$V_{DS} = 75V, V_{GS} = 0V$	-	-	1	^
Zero Gate voltage Drain Current	$V_{DS} = 75V, T_{C} = 150^{\circ}C$	-	-	500	μА
Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current				

#### **On Characteristics**

١	V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.5	4.5	٧
F	R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_{D} = 80A$		3.7	4.7	mΩ
Ć	9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_D = 80A$ (Note 4)		150	-	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	-	7080	9415	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz	-	870	1155	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/2	-	410	615	pF

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	100	210	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 37.5V, I_{D} = 80A$		-	147	304	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{GEN} = 25\Omega, V_{GS} = 10V$		-	220	450	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)	-	114	238	ns
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-	117	152	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 60V, I_{D} = 80A$		-	37	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V	(Note 4, 5)	=	32	-	nC

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	164	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	656	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 80A	-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 80A	-	45	-	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s   (Note 4)$	-	66	-	nC

#### Notes

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Repetitive Rating: Pulse width limited by maximum junction temperature

<sup>2.</sup> L = 0.21mH, I  $_{AS}$  = 80A, V  $_{DD}$  = 50V, R  $_{G}$  = 25  $\!\Omega$  , Starting T  $_{J}$  = 25  $\!^{\circ}C$ 

<sup>3.</sup>  $I_{SD} \le 75 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$ 

<sup>4.</sup> Pulse Test: Pulse width  $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$ 

<sup>5.</sup> Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

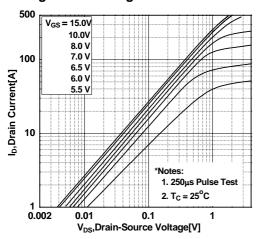


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

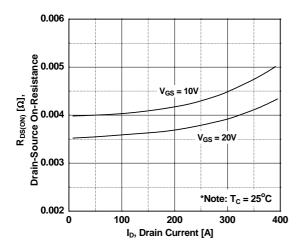


Figure 5. Capacitance Characteristics

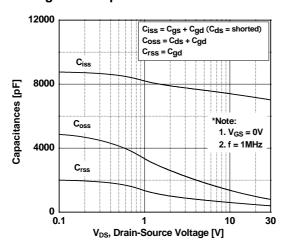


Figure 2. Transfer Characteristics

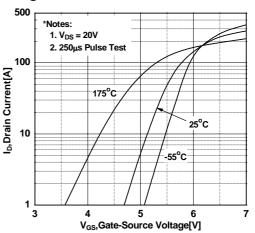


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

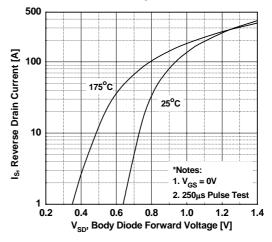
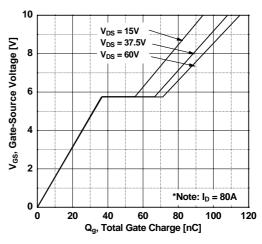


Figure 6. Gate Charge Characteristics



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## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

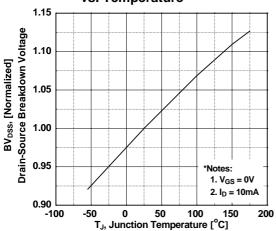


Figure 8. On-Resistance Variation vs. Temperature

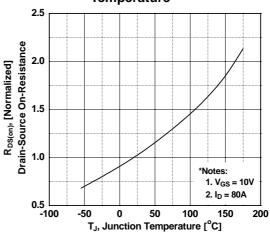


Figure 9. Maximum Safe Operating Area

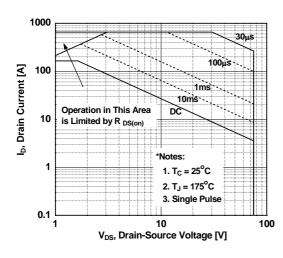


Figure 10. Maximum Drain Current vs. Case Temperature

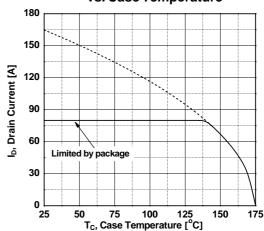
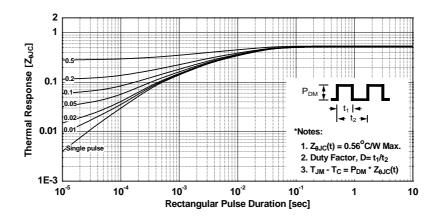
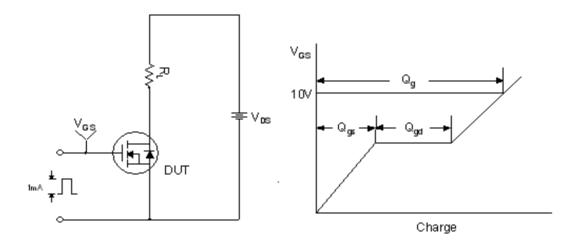


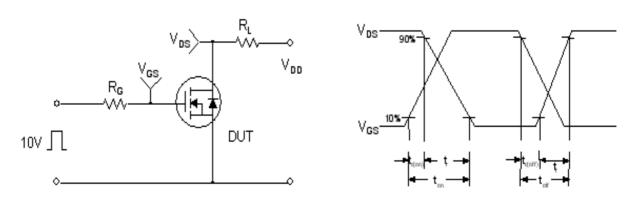
Figure 11. Transient Thermal Response Curve



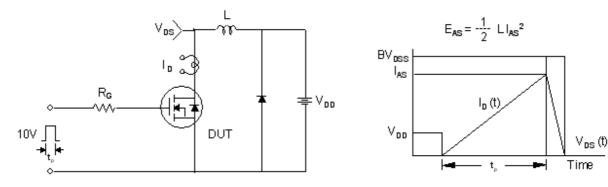
### **Gate Charge Test Circuit & Waveform**



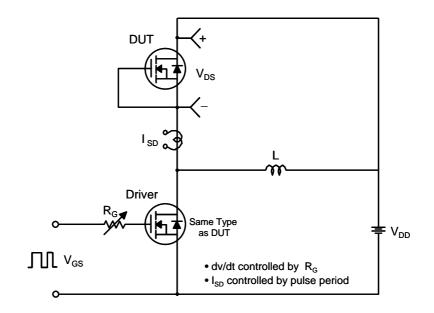
#### **Resistive Switching Test Circuit & Waveforms**

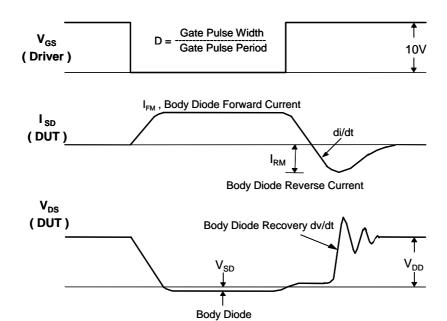


**Unclamped Inductive Switching Test Circuit & Waveforms** 



#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

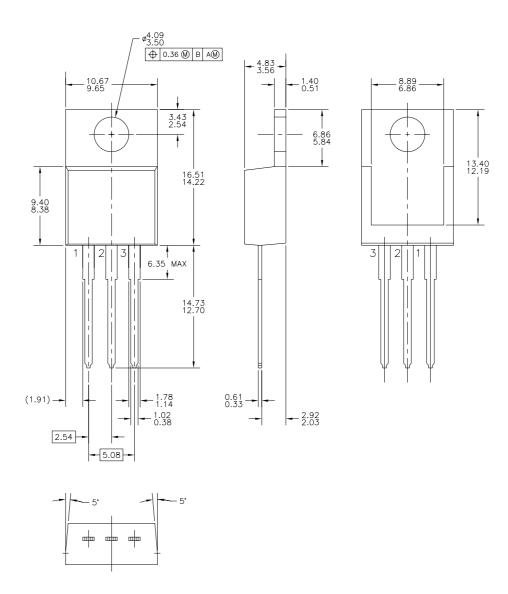




Forward Voltage Drop

## **Mechanical Dimensions**

## TO-220







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